

# Slit Beam Shaping for Femtosecond Laser Point-by-Point Inscription of High-Quality Fiber Bragg Gratings

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**Abstract**—Fiber Bragg gratings (FBGs) inscribed by using femtosecond laser point-by-point (PbP) technology typically have high birefringence due to the elliptical cross-sectional pattern of refractive index modulations (RIMs) created in the fiber core. Additionally, a highly reflective type II PbP FBG, which has a large coupling coefficient, also exhibits large insertion loss due to the limited RIM area induced by a single femtosecond laser pulse. Here we demonstrate a slit beam shaping method for femtosecond laser PbP inscription of high-quality FBGs, featuring by high reflectivity, low insertion loss, and low birefringence. The slit beam shaping method could reduce the ellipticity in the cross-sectional pattern of RIMs without reducing the cross-sectional area, leading to low birefringence and low insertion loss. The experimental results agree well with numerical calculations. Hence, a high-quality type II PbP FBG, which has high reflectivity of 99.12% (i.e., Bragg resonance attenuation of 20.52 dB), low insertion loss of 0.30 dB, and low birefringence of  $1.86 \times 10^{-6}$ , was successfully created by use of a slit width of 0.8 mm. Moreover, an enlarged cross-sectional area was created by use of a slit width of 0.2 mm, resulting in a high ratio of 172.46 of the coupling strength coefficient to the scattering loss coefficient in the fabricated PbP FBG, which exhibits very high reflectivity of 99.99% (i.e., a strong Bragg resonance attenuation of 46.65 dB) and low insertion loss of 0.27 dB. Such high-quality FBGs will be promising in many applications, such as optical fiber communications, sensors, and lasers.

**Index Terms**—Fiber Bragg gratings, laser materials processing, slit beam shaping.

## I. INTRODUCTION

HIGH-QUALITY fiber Bragg gratings (FBGs) with high reflectivity, low insertion loss, and low birefringence have received much attention in many areas, such as fiber-optic communications, sensors and lasers. The insertion loss (IL), as one of the key parameters of FBGs, can restrict the multiplexing capability of FBG sensors arrays and the efficiency of fiber lasers [1], [2]. The polarization dependent loss (PDL), resulting from the laser-induced birefringence in FBGs, will deteriorate the bit error rate in optical transmission systems [3]. To date, various methods have been proposed for fabricating high-quality FBGs. For example, the most commonly used method is the inscription of FBGs by femtosecond laser exposure through a phase mask [4], [5]. However, it is difficult to use this method for creating a wavelength-division-multiplexed FBG array. Additionally, the femtosecond laser point-by-point (PbP) or line-by-line (LbL) inscription method was used to create FBGs with various Bragg wavelengths [1], [2], [6]–[9]. In comparison with the LbL inscription method, the PbP inscription method has a similar flexibility but a much higher efficiency in grating fabrication, and hence attracted much interest in recent years [1], [10]–[12]. Nevertheless, the cross-sectional pattern of refractive index modulations (RIMs) induced by a single femtosecond laser pulse is elliptical, resulting in high birefringence [2], [9]. Moreover, the RIM area is limited, resulting in a low ratio of the coupling strength coefficient to the scattering loss coefficient  $\kappa/\alpha$  (i.e.,  $< 100$ ) [13], [14]. In our previous work, we demonstrated a method for reducing the PDL (as low as 1.18 dB) and increasing the  $\kappa/\alpha$  of PbP FBGs based on a symmetric cross-sectional pattern of RIMs formed in parallel-integrated FBGs [12]. However, it is complicated and also inefficient for fabricating these special spatial-distributed parallel-integrated FBGs.

Spatial beam shaping method has been developed for creating PbP FBGs by use of femtosecond laser inscription [14]–[16]. Various optical setups, such as two cylindrical lenses [17], a spatial light modulator (SLM) [18], [19] and a slit [20], are used for spatial beam shaping. Recently, the slit beam shaping method was proposed to create near-circular cross-sectional patterns of PbP FBG [16]. However, the quality of the fabricated FBG

Manuscript received January 29, 2021; revised April 8, 2021 and May 17, 2021; accepted May 18, 2021. Date of publication May 21, 2021; date of current version August 2, 2021. This work was supported in part by the National Natural Science Foundation of China under Grants U1913212, 61875128, and 62005170, in part by Department of Science and Technology of Guangdong Province under Grants 2019TQ05X113, 2019A1515111114, and 2019A1515011393, in part by Shenzhen Science and Technology Program under Grants RCYX20200714114538160, JCYJ20200109114201731, and JCYJ20180507182058432, and in part by China Postdoctoral Science Foundation under Grant 2019M663049. (Corresponding author: Jun He).

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Color versions of one or more figures in this article are available at <https://doi.org/10.1109/JLT.2021.3082566>.

Digital Object Identifier 10.1109/JLT.2021.3082566

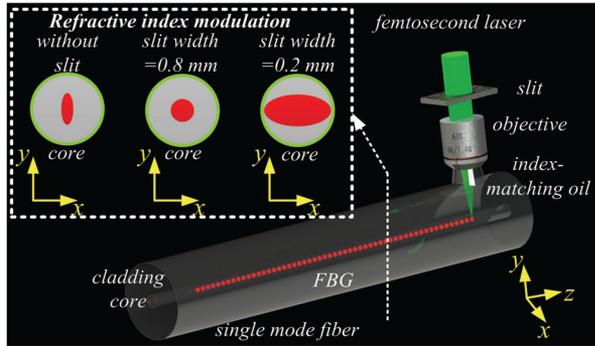


Fig. 1. Schematics of the working principle and experimental setup for fabricating high-quality FBGs using femtosecond laser PbP technology and slit beam shaping method. (Insert: the cross-sectional view of the refractive index modulation created by use of various slit widths.)

mentioned in this paper is quite low, exhibiting low reflectivity of  $\sim 60\%$  (i.e., Bragg resonance attenuation of  $\sim 4$  dB).

In this letter, we further developed the slit beam shaping method for femtosecond laser PbP inscription of high-quality FBGs. The slit beam shaping method reduces the ellipticity in the cross-sectional pattern of RIMs without decreasing the laser beam focus, and leads to low birefringence together with low insertion loss. As a result, a high-quality FBG, which has high reflectivity of 20.56 dB, low insertion loss of 0.30 dB, and low birefringence of  $1.86 \times 10^{-6}$ , was successfully fabricated by using this method with a slit width of 0.8 mm. Moreover, an enlarged cross-sectional area of RIMs could be created by a slit width of 0.2 mm, resulting in a high  $\kappa/\alpha$  of 172.46 in the fabricated PbP FBG.

## II. SETUP OF FABRICATING FBG BY USING SLIT BEAM SHAPING

The principle and experimental setup used for fabricating high-quality FBGs by using slit beam shaping method and femtosecond laser PbP technology were exhibited in Fig. 1. A frequency-doubled regenerative amplified Yb:KGW (Kd(WO<sub>3</sub>)) femtosecond laser (Pharos, Light-conversion) with a central wavelength of 514 nm, a pulse width of 290 fs, a repetition rate of 200 kHz, and a laser spot diameter of 3 mm was employed. The repetition rate was lowered to 1 kHz using a pulse picker. Then, an adjustable mechanical slit (Thorlabs, VA100) was inserted in front of the objective. The slit position and inclination was set to ensure the normal incidence of beam center, and the slit orientation was set to parallel to the fiber axis. Subsequently, the laser beam was focused into a single mode fiber (SMF, Corning SMF-28e) by use of a  $100\times$  Leica oil-immersion objective with a numerical aperture of 1.25. The output face of the objective and the SMF were immersed in the index matching oil to reduce the aberration at silica/air interfaces. The SMF was moved at a constant velocity using an assembled 3D translation stage (Aerotech ABL15010, ANT130LZS, and ANT130V-5). Consequently, an FBG (i.e., a serial of periodic RIMs) was created in the fiber core along the fiber axis by femtosecond laser pulses. As shown in the inset of Fig. 1, a near-circular cross-sectional pattern of the

TABLE I  
PARAMETER COMPARISON OF FIVE FBGs (S1-S5)

FBG	W/ mm	E/ nJ	h/ $\mu\text{m}$	w/ $\mu\text{m}$	$\beta$	A/ $\mu\text{m}^2$	$\Delta n_B$	PDL
S1	/	35	3.02	0.86	2.51	2.04	$7.57 \times 10^{-5}$	12.85
S2	2	32	2.80	1.10	1.54	2.42	$5.40 \times 10^{-5}$	11.44
S3	1	31	1.84	1.51	0.22	2.18	$1.30 \times 10^{-5}$	3.48
S4	0.8	30	1.64	1.76	0.07	2.27	$1.86 \times 10^{-6}$	1.50
S5	0.5	39	1.40	2.54	0.81	2.79	$3.60 \times 10^{-5}$	9.06

laser-induced RIM can be obtained after slit beam shaping. The ellipticity in the cross-sectional pattern of RIM can be reduced by carefully adjusting the slit width. Moreover, the enlarged area of cross-sectional pattern of RIM can be obtained by using an appropriate slit width.

## III. RESULTS AND DISCUSSION

### A. Inscription of FBG With Low Birefringence

At first, we investigated the slit beam shaping method to reduce the laser-induced birefringence in the PbP FBGs. A FBG (i.e., S1) was inscribed by using femtosecond laser PbP technology merely. And four FBGs (i.e., S2, S3, S4, and S5) were inscribed by using femtosecond laser PbP technology and slit beam shaping with a decreasing slit width  $W$  shown in Table I. Note that five FBGs, i.e., one FBG S1 inscribed without slit beam shaping and four FBGs S2-S5 inscribed with slit beam shaping, have the same grating pitch of  $1.070 \mu\text{m}$  and the same grating length of 4 mm, and are fabricated by using the same objective. To observe the FBG cross section, we cleaved the FBG at the grating region via a fiber-processing system, consisting of a fiber cleaver (Sumitomo, FC-6S), a microscope (Sunway), and a fiber visual fault locator. The grating region of an FBG could be found by using the visual fault locator, since the red light is scattered out of the fiber core at the FBG position, and then the grating region was held by fiber cleaver. The FBGs S1-S5 were cleaved transversally, and then a microscope (Leica, DM2700MH) with an oil-immersion objective (Leica,  $100\times$ , numerical aperture: 1.32) were employed to obtain the cross-sectional images of FBGs. Figs. 2(a1)–(a5) exhibit the cross-sectional microscope images of the five fabricated FBGs S1-S5, respectively, and Figs. 2(b1)–(b5) exhibit the corresponding polarization-resolved transmission spectra and PDL spectra. Note that Figs. 2(b1)–(b5) were directly measured by a Muller-matrix-based commercial polarization analysis system, which consists of a tunable laser (Agilent, 81940A), a polarization synthesizer (Agilent, N7786B), and an optical power meter (Agilent, N7744A). The Bragg wavelengths of these FBGs were determined by applying Gaussian fits on the grating transmission spectra. The five FBGs S1-S5 have similar dip attenuation of  $-20$  dB, and the on-target single pulse energy  $E$  used for fabricating S1-S5 was shown in Table I. All of them are type II gratings.

Moreover, as shown in Figs. 2(a1)–(a5), the cross-sectional patterns of RIMs are elliptical with various heights  $h$  and widths  $w$ . The ellipticity  $\beta$  and area  $A$  of the cross-sectional patterns of RIMs can be roughly calculated by  $\beta = h/w - 1$  and  $A = \pi(h \times w)/4$ , respectively. In addition, the parameters of cross-sectional patterns of RIMs in FBGs S1-S5 were shown in Table I.

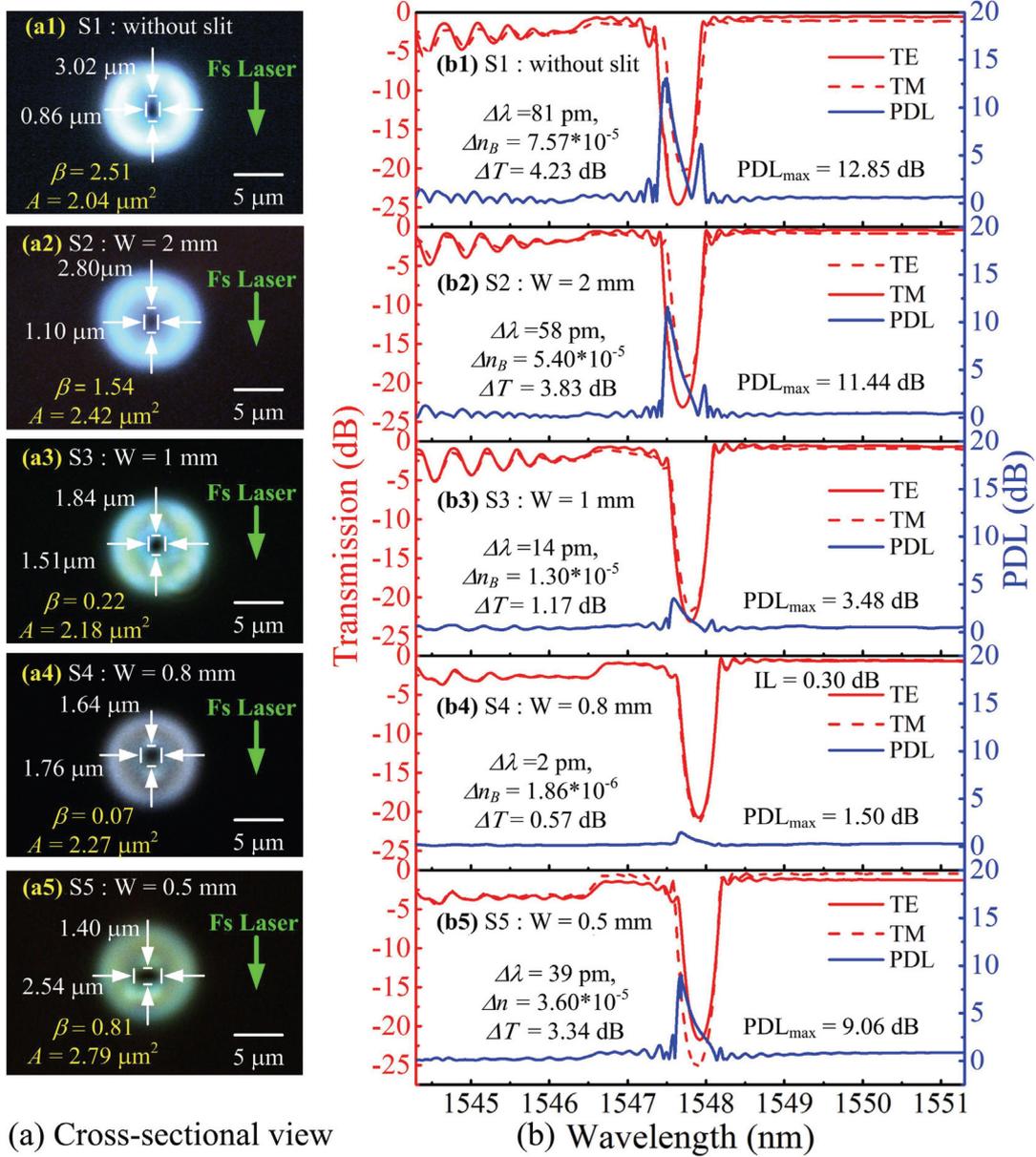


Fig. 2. An FBG S1 inscribed without slit beam shaping and four FBGs S2-S5 inscribed using slit beam shaping with a decreasing slit width ( $W$ ) of 2, 1, 0.8, and 0.5 mm, respectively. (a) Cross-sectional-view microscope images and (b) corresponding transmission spectra of two orthogonal linear polarization modes (TE and TM), and PDL spectra of FBGs S1-S5.

In case the slit beam shaping is used and the slit width  $W$  is reduced, the height of RIM  $h$  decreases and the width of RIM  $w$  increases, leading to a decrease in the ellipticity of RIM  $\beta$ . For example, as shown in Fig. 2(a1), the FBG S1 inscribed without slit beam shaping has a large ellipticity of 2.51, whereas as shown in Fig. 2(a4), the FBG S4 inscribed with a slit width of 0.8 mm has a minimized ellipticity of 0.07, and the RIM exhibits a near-circular cross-sectional pattern. Additionally, the ellipticity increases again when the slit width  $W$  is further reduced to 0.5 mm. Hence, the ellipticity in the cross-sectional pattern of RIM can be reduced to the minimum by using a slit with an appropriate width.

The birefringence in FBGs can be calculated from  $\Delta n_B = \Delta\lambda/\Lambda$ , where  $\Lambda$  is the grating pitch,  $\Delta\lambda$  is the Bragg wavelength difference between two orthogonal linear polarization modes

(i.e., TE and TM) [2]. Moreover,  $\Delta T$  in Fig. 2(b) is the difference in transmission dip attenuation between TE and TM modes. The parameters of the transmission spectra and PDL spectra of FBGs S1-S5 were shown in Table I and Fig. 2(b). Note that FBG S4 fabricated with a slit width of 0.8 mm exhibits a reduced birefringence  $\Delta n_B$  of  $1.86 \times 10^{-6}$  and a reduced PDL of 1.50 dB. It means the birefringence can be reduced effectively by use of the slit beam shaping method via decreasing the ellipticity in the cross-sectional pattern of RIMs.

#### B. Simulation of Birefringence Effects From RIMs in FBG

Furthermore, we studied the influence of ellipticity in the cross-sectional pattern of RIMs on the birefringence in a PbP FBG by use of a commercial finite element analysis tool

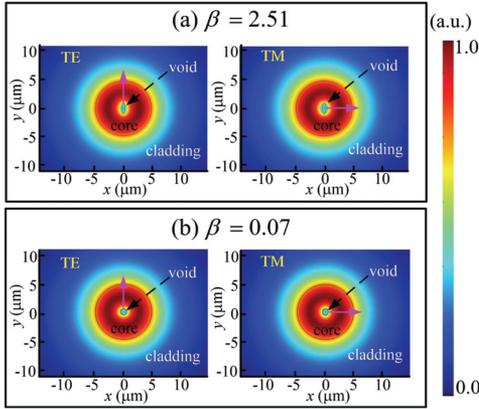


Fig. 3. The simulation of energy flux profiles of two orthogonal linear polarization modes (TE and TM) propagating in the FBGs formed by (a) a series of microvoids with an ellipticity of 2.51 and an area of  $0.60 \mu\text{m}^2$  and (b) a series of microvoids with a minimized ellipticity of 0.07 and the same area of  $0.60 \mu\text{m}^2$ .

(COMSOL). The RIM model consists of a small microvoid and a surrounded densified region, which was created in the fiber core by high-energy laser-induced micro-explosion. The height and width of the microvoid can be estimated as one half of the densified region [21]. Moreover, the index change in the microvoid is at least one order of magnitude larger than that in the densified region. As a result, the densified region was neglected in the modeling to simplify the calculations. The SMF-28e parameters, i.e., a core diameter of  $8.3 \mu\text{m}$ , a refractive index of 1.44940 and 1.44421 at the wavelength of 1550 nm in fiber core and fiber cladding, respectively, were used in the model. In addition, the RIM profile could be treated as invariants along fiber axis for mode calculation, as reported by Nemanja *et al.* [2]. The averaged refractive index  $n_{ave}$  of a grating pitch in PbP FBG could be approximated as

$$n_{ave} = \frac{w_v \cdot n_v + (\Lambda - w_v) \cdot n_{co}}{\Lambda} \quad (1)$$

where  $n_{co}$  is the refractive index of the fiber core,  $n_v$  is the refractive index of the microvoid (i.e.,  $n_v = 1.0$ ),  $w_v$  is the width of the microvoid and  $\Lambda$  is the grating pitch. The birefringence is given by  $\Delta n_B = n_{TE} - n_{TM}$ , where  $n_{TE}$  and  $n_{TM}$  are the effective indices of the two orthogonal linear polarization states (i.e., TE and TM). To study the effect of area and ellipticity in the cross-sectional pattern of a microvoid on the birefringence, a scan of area  $A_v$  was conducted with a constant ellipticity. Then, we repeated the previous process with different ellipticity. The simulation results of birefringence effects from RIMs can be obtained. The mode field profiles and the effective indices of TE and TM modes at the Bragg wavelength of 1547.70 nm were numerically calculated. Fig. 3(a) shows the energy flux profiles of TE and TM modes propagating in a PbP FBG formed by a series of microvoids with an area of  $0.60 \mu\text{m}^2$  and an ellipticity of 2.51. The calculated birefringence ( $\Delta n_B = 7.4815 \times 10^{-5}$ ) agrees well with the measurement result of FBG S1 (i.e.,  $7.57 \times 10^{-5}$ ) with an ellipticity of 2.51. Additionally, Fig. 5(b) shows the energy flux profiles of TE and TM modes propagating in the FBG formed by a series of microvoids with

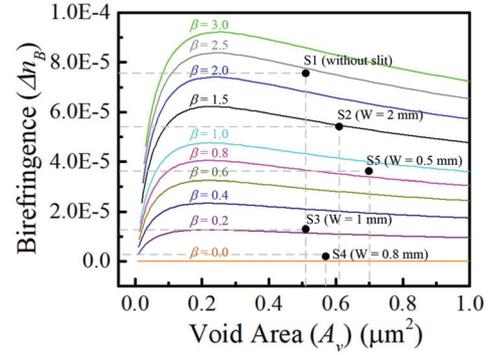


Fig. 4. Calculated birefringence  $\Delta n_B$  as functions of microvoid areas  $A_v$  with varying ellipticity  $\beta$ . Black dots show the measured birefringence in five fabricated PbP FBGs (i.e., S1-S5) with different ellipticity  $\beta$ .

TABLE II  
PARAMETER COMPARISON OF THREE FBGS (S6-S8)

FBG	$W/mm$	$E/nJ$	$h/\mu\text{m}$	$w/\mu\text{m}$	$A/\mu\text{m}^2$	$T_B/dB$	$T_{II}/dB$	$\kappa/\alpha$
S6	0.4	40.0	1.79	2.87	4.03	-25.67	0.44	58.36
S7	0.3	44.2	1.75	4.35	5.98	-32.01	0.46	69.59
S8	0.2	59.7	1.75	6.30	8.65	-46.65	0.27	172.46

the same area of  $0.60 \mu\text{m}^2$  but a minimized ellipticity of 0.07. Calculation results exhibit that the birefringence is extremely low (i.e.,  $\Delta n_B = 2 \times 10^{-9}$ ).

Fig. 4 shows the calculation results of the birefringence  $\Delta n_B$  at the Bragg wavelength of 1547.70 nm as functions of the microvoid area  $A_v$  with a series of ellipticities. Obviously, the birefringence  $\Delta n_B$  decreases in case the ellipticity  $\beta$  is reduced, and the birefringence disappears ( $\Delta n_B = 0$ ) when the ellipticity  $\beta$  equals to 0.00 (i.e., the cross-sectional pattern of the microvoid has a complete circular symmetry). Additionally, the microvoid area  $A_v$  can also affect the birefringence  $\Delta n_B$  in the PbP FBG. Nevertheless, the influence of  $A_v$  is relatively small when  $A_v$  is large enough (for example,  $A_v = 0.60 \mu\text{m}^2$  for a typical PbP FBG). The measured birefringence  $\Delta n_B$  in FBGs S1-S5, are also displayed in Fig. 4 (black dots), and the measured results agree well with the calculated results. Therefore, a low birefringent PbP FBG (i.e., S4,  $\Delta n_B = 1.86 \times 10^{-6}$ ) was achieved by reducing the ellipticity to 0.07 in the cross-sectional pattern of the microvoids with the proposed slit beam shaping method.

### C. Inscription of FBG With High $\kappa/\alpha$

Subsequently, we studied the slit beam shaping method to increase the RIM area. Three second-order PbP FBGs (i.e., S6, S7 and S8) were inscribed by using femtosecond laser PbP technology and slit beam shaping with decreasing slit width ( $W$ ) shown in Table II. Note that S6-S8 has the same grating pitch of  $1.070 \mu\text{m}$  and the same grating length of 4 mm. The on-target single pulse energy  $E$  used for fabricating S6-S8 was shown in Table II. All of them are type II gratings. Figs. 5(a1)–(a3) exhibit the cross-sectional microscope images of the three fabricated FBGs S6-S8, respectively. The width  $w$ , height  $h$ , and calculated area  $A$  in S6-S8 are displayed in Table II. Note

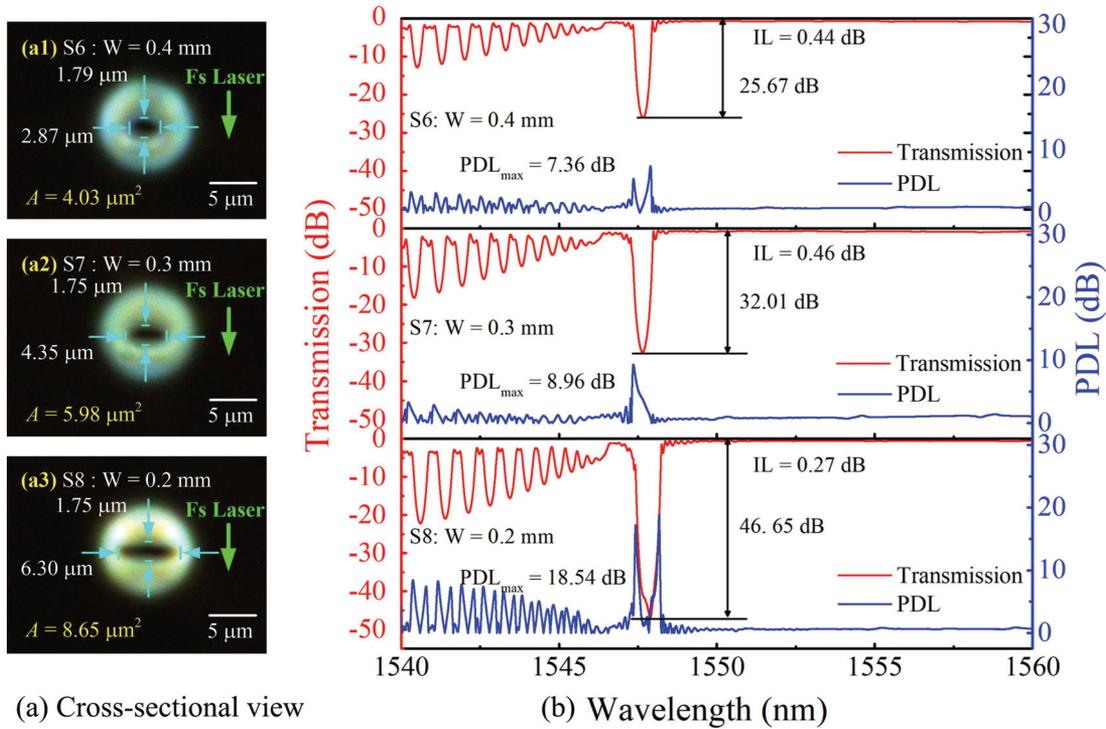


Fig. 5. Three PbP FBGs S6-S8 inscribed by using slit beam shaping with a decreasing slit width  $W$  of 0.4, 0.3, and 0.2 mm, respectively. (a) Cross-sectional-view microscope images, and (b) corresponding transmission and reflection spectra of S6-S8.

that an enlarged RIM area can be obtained using a slit with a decreasing slit width. Moreover, Figs. 5(b)–(b3) show the corresponding transmission and PDL spectra of S6-S8. The measured insertion loss and the dip attenuation S6, S7 and S8 are displayed in Fig. 5(b) and Table II. The ratio of the coupling strength coefficient to the scattering loss coefficient  $\kappa/\alpha$  is a crucial parameter of FBGs, which is identified as a figure of merit for determining the maximum reflectivity achievable with a FBG. The coupling coefficient  $\kappa$  and scattering loss coefficient  $\alpha$  can be expressed as

$$\alpha = \frac{\ln(T_{IL})}{-2L}, \quad (2)$$

$$\kappa = \frac{\ln(T_B)}{-2L}, \quad (3)$$

where  $T_{IL}$  is the insertion loss (transmission loss measured out-of-band),  $T_B$  is the Bragg resonance attenuation, and  $L$  is the grating length [13]. It is obvious a higher ratio of  $\kappa/\alpha$  will result in high reflectivity and low insertion loss in the fabricated PbP FBG.

The coupling coefficient  $\kappa$ , scattering loss coefficient  $\alpha$  and the ratio of  $\kappa/\alpha$  of the fabricated PbP FBGs of S6, S7 and S8 are calculated and shown in Table II. The maximum ratio of  $\kappa/\alpha$  can be obtained in S8, which is much larger than that (i.e., 70) of the FBG inscribed by use of a conventional femtosecond laser PbP technology [13].

Recently, cylindrical lens-based beam shaping method has also been demonstrated to fabricate a high-quality type II PbP FBG with high reflectivity of 99.99% (i.e., a strong Bragg resonance attenuation of  $\sim 47$  dB) and a low insertion loss of

$\sim 0.80$  dB [14]. However, the ratio of  $\kappa/\alpha$  in this PbP FBG was merely 58.75, and hence a long grating length of 10 mm was required to realize such a high-quality type II PbP FBG. These results illustrate that the slit beam shaping will be an effective way to enlarge the RIM area, leading to an increased ratio  $\kappa/\alpha$  in the fabricated PbP FBG. However, FBGs S6-S8 exhibit increasing cladding modes resonance, resulting from the decrease in circular symmetry of RIMs. Additionally, the PDLs in FBGs S6-S8 were measured and displayed in Fig. 5(b). It is obvious that the PDL increases with decreasing slit width due to the increasing ellipticity of the RIMs.

#### IV. CONCLUSION

In summary, we demonstrated the fabrication of high-quality FBGs with high reflectivity, low insertion loss, and low birefringence by use of a femtosecond laser PbP technology with a slit beam shaping method. The influence of the slit widths was experimentally studied. The slit beam shaping with an appropriate width could efficiently reduce the ellipticity and create a circular symmetry in the cross-sectional pattern of RIMs, resulting in a decrease in the birefringence. The experimental results agree well with the numerical calculations. Therefore, a high-quality PbP FBG, which has high reflectivity of 99.12% (i.e., Bragg resonance attenuation of 20.52 dB), low insertion loss of 0.30 dB, and low birefringence of  $1.86 \times 10^{-6}$ , was successfully created by using a slit width of 0.8 mm. Moreover, an enlarged cross-sectional area could be inscribed by use of a slit width of 0.2 mm, resulting in a high ratio of 172.46 of the coupling strength coefficient to the scattering loss coefficient in the fabricated PbP FBG, which has very high reflectivity of

99.99% (i.e., a strong Bragg resonance attenuation of 46.65 dB) and low insertion loss of 0.27 dB. Such high-quality FBGs could further be developed for many applications in optical fiber communications, sensors, and lasers.

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